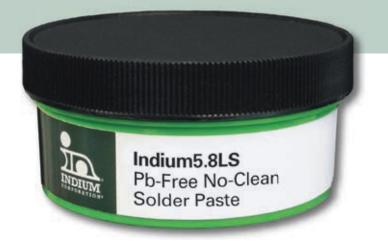
# Indium5.8LS

# **Pb-Free Solder Paste**

- Ultra-low flux/solder spatter
- Outstanding print characteristics
- Halogen-free







# **Product Information**

# Indium5.8LS Pb-Free Solder Paste

### Features

- Ultra-low flux spattering (ideal for applications with Au finger connectors)
- Ultra-low solder beading
- Halogen-free
- Superior stencil life
- Outstanding print characteristics
- Extremely wide process window

### Introduction

**Indium5.8LS** is a halogen-free, no-clean solder paste specifically formulated for low flux spatter. This material is designed to accommodate the higher processing temperatures required by the Sn/Ag/Cu, Sn/Ag, and other Pb-Free alloy systems in an air or nitrogen reflow atmosphere. This product formulation offers consistent, repeatable printing performance combined with long stencil and tack times to handle the rigors of today's high speed, as well as, high mix surface mount lines.

### Alloys

Indium Corporation manufactures low-oxide spherical powder composed of a variety of Pb-Free alloys that cover a broad range of melting temperatures. Type 4 and Type 3 powder are standard offerings with SAC305 & SAC387 alloys. The metal percent is the weight percent of the solder powder in the solder paste and is dependant upon the powder type and application. Standard product offerings are detailed in the following table below.

### **Standard Product Specifications**

Alloy	Metal Load	IPN
96.5Sn/3.0Ag/0.5Cu (SAC305)	88.5% (Type 4)	800105
96.5Sn/3.0Ag/0.5Cu (SAC305)	89.0% (Type 3)	83753

# Packaging

Standard packaging for stencil printing applications includes 4 oz. jars and 6 oz. or 12 oz. cartridges. Packaging for enclosed print head systems is also readily available. For dispensing applications, 10cc and 30cc syringes are standard. Other packaging options may be available upon request.

# **Storage and Handling Procedures**

Refrigerated storage is recommended throughout the shelf life of solder paste. The shelf life of **Indium5.8LS** is 6 months when stored at <10°C. Store syringes and cartridges tip down.

Remove solder paste from refrigeration at least two hours before use to allow the solder paste to reach an ambient working temperature. As the time to reach thermal equilibrium will vary with container size, verify solder paste temperature prior to use. Label jars and cartridges with the date and time of opening. For optimal solder paste performance, storage at ambient temperatures (21-25°C) should not exceed two weeks in duration.

# **Material Safety Data Sheets**

The MSDS for this product can be found online at http://www.indium.com/techlibrary/msds.php .

Bellcore and J-STD Tests & Results										
J-STD-004A (IPC-TM-650) Result J-STD-005 (IPC-TM-650) Result										
Flux Type (per J-STD-004A)*	ROLO	Typical Solder Paste Viscosity: Malcom (10rpm)								
Flux Induced Corrosion: Copper Mirror	L	88.5% metal load (Type 4) 89.0% metal load (Type 3)	1400 poise† 1600 poise†							
Presence of Halide Silver Chromate	Pass	Slump Test	Pass							
Fluoride Spot Test	Pass	Solder Ball Test	Pass							
Quantitative Halide Content	0%	Typical Tackiness	34 grams							
Post Reflow Flux Residue: ICA Test	46%	Wetting Test	Pass							
SIR	Pass	Bellcore GR-78	Result							
* J-STD-004A has replaced J-STD-004 and is more stringent in its requirements.		SIR	Pass							
<sup>†</sup> Pending statistical validation		Electromigration	Pass							
All information is for reference only. Not to be	e used as incoming p	roduct specifications.								

# Indium5.8LS Pb-Free Solder Paste

# Printing

# Stencil Design:

Electroformed and laser cut/electropolished stencils produce the best printing characteristics among stencil types. Stencil aperture design is a crucial step in optimizing the print process. The following are a few general recommendations:

- Discrete components A 10-20% reduction of stencil aperture has significantly reduced or eliminated the occurrence of mid-chip solder beads. The "home plate" design is a common method for achieving this reduction.
- Fine pitch components A surface area reduction is recommended for apertures of 20 mil pitch and finer. This reduction will help minimize solder balling and bridging that can lead to electrical shorts. The amount of reduction necessary is process dependent (5-15% is common).
- For adequate release of solder paste from stencil apertures, a minimum aspect ratio of 1.5 is required. The aspect ratio is defined as the width of the aperture divided by the thickness of the stencil.

# **Printer Operation:**

The following are general recommendations for stencil printer optimization. Adjustments may be necessary based on specific process requirement:

Solder Paste Bead Size:	20-25mm diameter
Print Speed:	25-150mm/sec
Squeegee Pressure:	0.018-0.027kg/mm of blade length
Underside Stencil Wipe:	Once every 10-25 prints
Solder Paste Stencil Life:	>8 hrs. @ 30-60% RH & 22°-28°C

# Cleaning

**Indium5.8LS** is designed for no-clean applications, however the flux can be removed if necessary by using a commercially available flux residue remover.

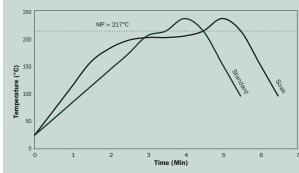
**Stencil Cleaning:** This is best performed using isopropyl alcohol (IPA) as a solvent. Most commercially available stencil cleaners work well.

# **Compatible Products**

- Rework Flux: TACFlux® 018, TACFlux® 020B
- Wave Flux: WF-7742, WF-9942
- Cored Wire: CW-801

# Reflow

### **Recommended Profile:**



The stated profile recommendations apply to most Pb-Free alloys in the Sn/Ag/Cu (SAC) alloy system, including SAC305 (96.5Sn/3.0Ag/0.5Cu). This can be used as a general guideline in establishing a reflow profile when using **Indium5.8LS** Solder Paste. Deviations from these recommendations are acceptable, and may be necessary, based on specific process requirements, including board size, thickness & density.

# **Heating Stage:**

A linear ramp rate of 0.5°- 2.0°C/second allows gradual evaporation of volatile flux constituents and helps minimize defects such as solder balling and/or beading and bridging resulting from hot slump. It also prevents unnecessary depletion of fluxing capacity when a high peak temperature and extended time above liquidus is used. A profile with a soak between 200°-210°C for up to 2 minutes can be implemented to reduce void formation on BGA & CSP type devices. A short soak of 20-30 seconds just below the melting point of the solder can help minimize tombstoning.

# Liquidus Stage:

A peak temperature of 12° to 43°C above the melting point of the solder alloy is recommended to achieve acceptable wetting and form a quality solder joint. The time above liquidus (TAL) should be 30–90 seconds. A peak temperature and TAL above these recommendations can result in excessive intermetallic formation that can decrease solder joint reliability.

# **Cooling Stage:**

A rapid cool down (4-6°C/second) is desired to form a fine grain structure. Slow cooling will form a large grain structure, which typically exhibits poor fatigue resistance.

This product data sheet is provided for general information only. It is not intended, described which are sold subject exclusively to written warranties and limitations and shall not be construed, to warrant or guarantee the performance of the products thereon included in product packaging and invoices.

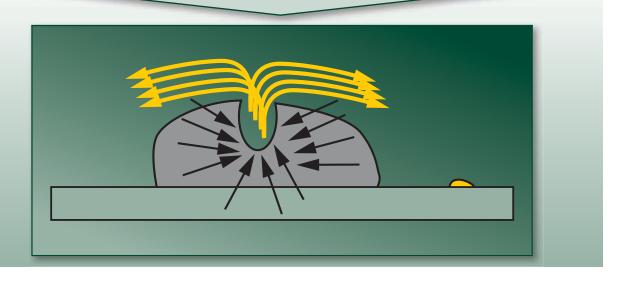


# **5.8LS Product Level Testing** Low Flux and Solder Spatter

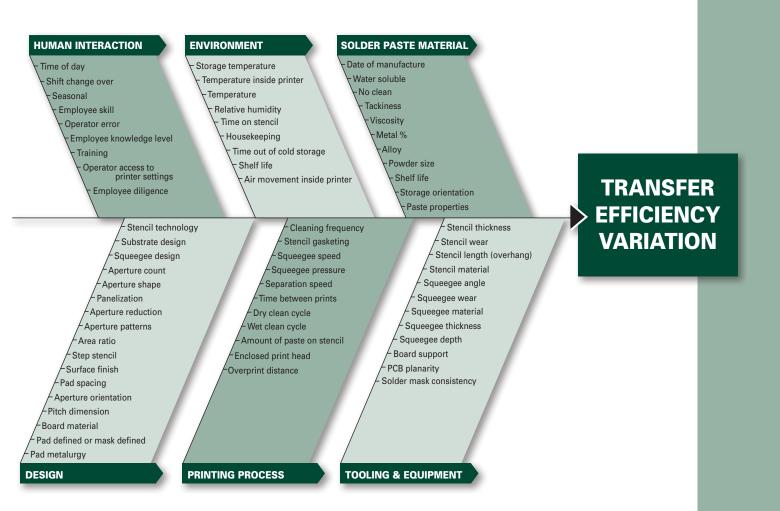
A major memory module manufacturer was able to reduce their flux/solder spatter defects from 10% to 1% through the implementation of **Indium5.8LS** and process optimization.



One major cause of flux and solder spatter occurs at the point of solder paste reflow. As the solder coalesces, it can cause flux remnant to "explode" outward and land onto nearby Au fingers. Solder paste fluxes designed with unique solvents and activators, such as **Indium5.8LS**, can provide a significant reduction in flux/solder spatter.



# **Ultra-Fine Pitch Printing**



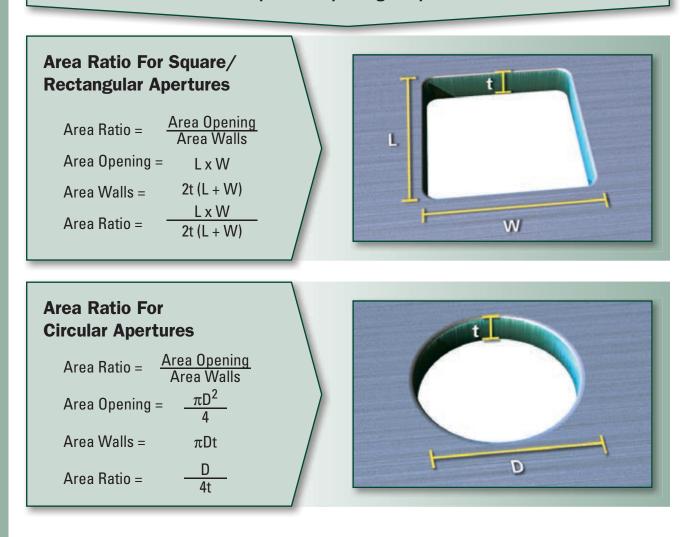
Solder Powder Reference												
Solder Powder Size Stencil Printing Dispensing												
J-STD-005	Diamete	Diameter Range		e Width	Particles to	Span Width	Needle Size # of L					
Designation	(mic	rons)	Microns	Inches	Smallest	Smallest Largest		ID (microns)	Particles			
3	25	45	250	0.010	10.00	5.60	22	410	9.1			
4	20	38	225	0.009	11.25	6.00	23	330	8.6			
5	15	25	200	0.008	13.30	8.00	25	250	10.0			
6	5	15	175	0.007	35.00	11.67	27	200	13.3			

INDIUM CORPORATION

# **Ultra-Fine Pitch Printing**

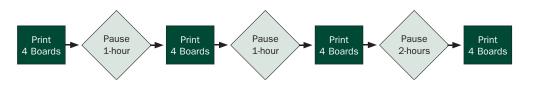
To ensure that a consistent volume of solder paste is printed onto the board, it is essential to design the stencil according to industry guidelines:

Area Ratio  $\geq$  0.66 Minimum number of solder particles spanning an aperture should be at least 4-5

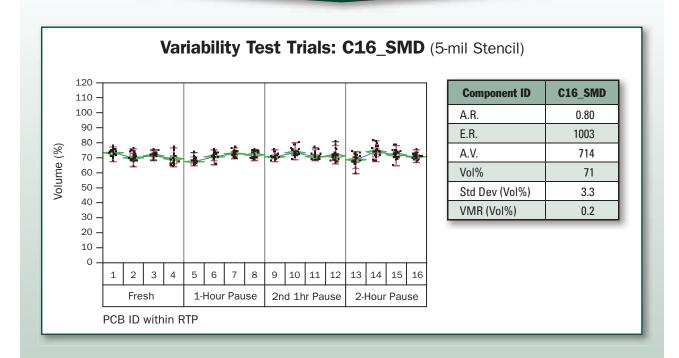


Sample Area Ratio Chart												
Pad Size (mm)         0.05         0.10         0.15         01005         0.20         0.25         0201         0.30         0.35         0.40         0.45         0.45											0.50	
Aperture Width (mil)	2.0	3.9	5.9	7 x 8	7.9	9.8	10 x 12	11.8	13.8	15.7	17.7	19.7
Stencil Thickness (5.0 mil)	0.10	0.20	0.30	0.37	0.39	0.49	0.55	0.59	0.69	0.79	0.89	0.98
Stencil Thickness (4.5 mil)	0.11	0.22	0.33	0.41	0.44	0.55	0.61	0.66	0.77	0.87	0.98	1.09
Stencil Thickness (4.0 mil)	0.12	0.25	0.37	0.47	0.49	0.62	0.68	0.74	0.86	0.98	1.11	1.23
Stencil Thickness (3.5 mil)	0.14	0.28	0.42	0.53	0.56	0.70	0.78	0.84	0.98	1.12	1.27	1.41
Stencil Thickness (3.0 mil)	0.16	0.33	0.49	0.62	0.66	0.82	0.91	0.98	1.15	1.31	1.48	1.64
Stencil Thickness (2.5 mil)	0.20	0.39	0.59	0.75	0.79	0.98	1.09	1.18	1.38	1.57	1.77	1.97

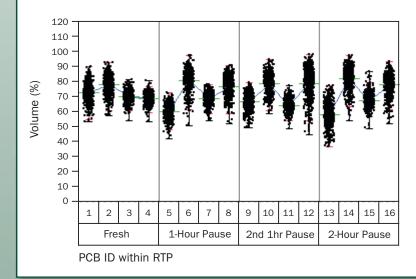
# **Response-to-Pause Procedure**



### Indium5.8LS



### Variability Test Trials: CSP12 (5-mil Stencil)



Component ID	CSP12
A.R.	0.60
E.R.	564
A.V.	404
Vol%	72
Std Dev (Vol%)	9.6
VMR (Vol%)	1.3



# Wide Reflow Process Window

#### Section #1 – Preheat:

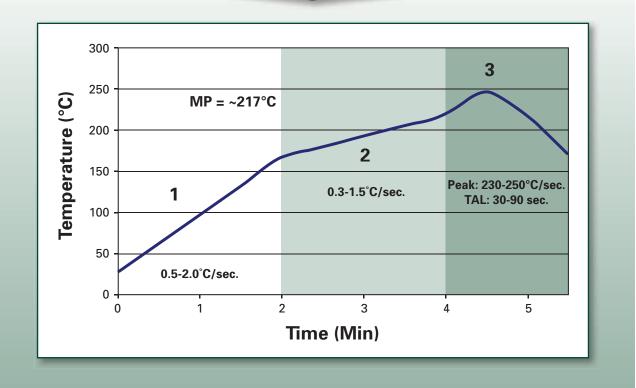
- **Slow Ramp Rate** Minimizes paste slump and flux spattering. Fewer shorts, solder balls, and solder beads.
- **Fast Ramp Rate** Minimizes additional oxidation on parts and boards. May help soldering of highly oxidized components.

#### Section #2 – Soak:

- **Short Soak Time** Minimizes oxidation and provides best opportunity for good wetting and shiny solder joints.
- Long Soak Time Minimizes tombstoning and voiding. Could negatively impact wetting.

#### Section #3 – Time Above Liquidus (TAL)/Peak:

- Short TAL/Low Peak Minimizes voiding and thermal damage to components/substrates.
- Long TAL/High Peak Improves solder coalescence but could result in dewetting if too long/high.



# **5.8LS Product Level Testing**

### Copper Mirror (Test #2.3.32)

**Objective:** The purpose of this test is to determine the corrosive (free-halide) properties of a flux.

**Procedure:** Flux is applied to a coppercoated glass slide and sits in a controlled environment for 24 hours. The flux is cleaned and the copper inspected for corrosion. Results: Pass, (L)

# Quantitative Halides (Cl, Br, Fl) (Test #2.3.28.1)

**Objective:** The purpose of this test is to determine the total halide concentration of a flux.

**Procedure:** Flux is dissolved to a pre-determined concentration. Extracted solutions are then analyzed using an lon Chromatograph with 3 to 5 level calibration. Total halide content is calculated and reported at Cl<sup>-</sup> equivalent.

Results: Total Halides = 0.0% Cl<sup>-</sup> Equivalent

# Qualitative Corrosion (Test #2.6.15)

**Objective:** The purpose of this test is to determine the corrosive properties of the flux residues under extreme environmental conditions.

**Procedure:** Solder paste is reflowed onto a sheet of copper and exposed to 40°C and 93% RH for 10 days. Coupon is then investigated for any signs of Cu corrosion.





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# **5.8LS Product Level Testing**

# Surface Insulation Resistance (Test #2.6.3.3)

**Objective:** The purpose of this test is to determine the Surface Insulation Resistance (SIR) of the flux residue after paste reflow.

#### Procedure: Paste is

stenciled onto the test board and reflowed. The un-cleaned board is then sent to outside laboratory for testing.

Surfa	ace Insulat	ion Resistand	e (SIR), IPC-	TM-650 Metl	10d 2.6.3.3 R	esults
Coupon	168 Hours	Final				
1	А	1.2E+10	1.1E+09	1.9E+09	1.9E+09	8.2E+12
1	В	5.7E+11	1.4E+09	2.6E+09	2.9E+09	7.6E+12
1	С	1.2E+12	1.3E+09	2.4E+09	2.5E+09	8.2E+12
1	D	3.6E+10	1.5E+09	2.5E+09	2.8E+09	7.5E+12
2	А	4.1E+12	1.3E+09	2.2E+09	2.1E+09	9.1E+12
2	В	5.0E+12	1.6E+09	2.8E+09	3.2E+09	7.5E+12
2	С	1.2E+13	1.4E+09	2.3E+09	2.4E+09	7.0E+12
2	D	6.1E+12	1.5E+09	2.4E+09	2.7E+09	2.4E+12
3	А	1.6E+11	1.4E+09	2.2E+09	2.3E+09	9.5E+12
3	В	8.8E+12	1.0E+09	2.4E+09	2.6E+09	8.7E+12
3	С	1.3E+09	1.1E+09	2.2E+09	2.3E+09	8.6E+12
3	D	1.6E+09	1.4E+09	2.4E+09	2.7E+09	9.1E+12
Control 1	А	5.5E+12	3.6E+10	2.3E+10	2.0E+10	1.7E+13
Control 1	В	1.6E+12	4.1E+10	2.5E+10	2.3E+10	4.8E+13
Control 1	С	5.0E+12	3.9E+10	2.4E+10	2.2E+10	4.3E+12
Control 1	D	4.7E+12	3.8E+10	2.5E+10	2.3E+10	1.8E+13
Control 2	А	3.4E+12	3.4E+10	2.3E+10	2.0E+10	1.2E+13
Control 2	В	2.7E+12	3.5E+10	2.4E+10	2.2E+10	1.6E+12
Control 2	С	9.3E+10	2.4E+10	2.5E+10	2.1E+10	8.6E+12
Control 2	D	3.0E+13	3.7E+10	2.4E+10	2.2E+10	2.1E+12

**Results: Pass** 

### **Results: Pass**

Electrochemical Migration Resistance, IPC-TM-650 Method 2.6.14.1 Results

# Electrochemical Migration (Test #2.6.14.1)

**Objective:** The purpose of this test is to determine the Electrochemical Migration and SIR of the flux residue after paste reflow.

#### Procedure: Paste is

stenciled onto the test board and reflowed. The un-cleaned board is then sent to outside laboratory for testing.

Test Sample	Initial resistance value after 96 hour stabilization with no bias (Ohm)	Final resistance value after 500 hours at test conditions (Ohm)
1	1.3E+11	5.78E+10
2	1.84E+11	1.87E+10
3	1.71E+11	7.62E+10
4	1.23E+11	5.50E+10
5	8.46E+09	1.50E+10
6	4.66E+11	9.04E+10
7	1.93E+11	1.16E+10
8	1.34E+09	2.71E+09
9	1.56E+11	7.48E+10
10	2.11E+11	1.03E+11
11	1.51E+09	9.87E+09
12	2.12E+11	7.25E+10
Geometric Mean (IR <sub>avg</sub> )	6.49E+10	3.68E+10
Control	Initial resistance value after 96 hour stabilization with no bias (Ohm)	Final resistance value after 500 hour at test conditions (Ohm)
Control		
	stabilization with no bias (Ohm)	at test conditions (Ohm)
1	stabilization with no bias (Ohm) 3.39E+10	at test conditions (Ohm) 1.36E+11
1 2	stabilization with no bias (Ohm) 3.39E+10 4.84E+10	at test conditions (Ohm) 1.36E+11 1.85+E11
1 2 3	stabilization with no bias (Ohm)           3.39E+10           4.84E+10           5.60E+10	at test conditions (Ohm) 1.36E+11 1.85+E11 1.86+E11
1 2 3 4	stabilization with no bias (Ohm)           3.39E+10           4.84E+10           5.60E+10           3.37E+10	at test conditions (Ohm) 1.36E+11 1.85+E11 1.86+E11 1.34+E11 1.34+E11
1 2 3 4 5	stabilization with no bias (Ohm)           3.39E+10           4.84E+10           5.60E+10           3.37E+10           4.13E+10	at test conditions (Ohm) 1.36E+11 1.85+E11 1.86+E11 1.34+E11 1.28+E11 1.28+E11
1 2 3 4 5 6	stabilization with no bias (Ohm)           3.39E+10           4.84E+10           5.60E+10           3.37E+10           4.13E+10           5.45E+10	at test conditions (Ohm) 1.36E+11 1.85+E11 1.86+E11 1.34+E11 1.28+E11 1.28+E11 1.83+E11
1 2 3 4 5 6 7	stabilization with no bias (Ohm)           3.39E+10           4.84E+10           5.60E+10           3.37E+10           4.13E+10           5.45E+10           5.82E+10	at test conditions (Ohm)           1.36E+11           1.85+E11           1.86+E11           1.34+E11           1.28+E11           1.83+E11           1.83+E11           1.81+E11
1 2 3 4 5 6 7 8	stabilization with no bias (Ohm)           3.39E+10           4.84E+10           5.60E+10           3.37E+10           4.13E+10           5.45E+10           5.82E+10           3.34E+10	at test conditions (0hm)           1.36E+11           1.85+E11           1.86+E11           1.34+E11           1.28+E11           1.83+E11           1.83+E11           1.81+E11           1.27+E11
1 2 3 4 5 6 7 8 9	stabilization with no bias (Ohm)           3.39E+10           4.84E+10           5.60E+10           3.37E+10           4.13E+10           5.45E+10           5.82E+10           3.34E+10           4.01E+10	at test conditions (0hm) 1.36E+11 1.85+E11 1.86+E11 1.34+E11 1.28+E11 1.83+E11 1.83+E11 1.81+E11 1.27+E11 1.16+E11
1 2 3 4 5 6 7 8 9 10	stabilization with no bias (Ohm)           3.39E+10           4.84E+10           5.60E+10           3.37E+10           4.13E+10           5.45E+10           3.34E+10           3.34E+10           5.48E+10	at test conditions (0hm)           1.36E+11           1.85+E11           1.86+E11           1.34+E11           1.28+E11           1.83+E11           1.81+E11           1.27+E11           1.16+E11           1.64+E11

### Metal Content (Test #2.2.20)

**Objective:** The purpose of this test is to determine the weight percent of metal in the solder paste. The percentage should not deviate more than +/-1% from the solder paste specification.

**Procedure:** A known weight of solder paste is reflowed in a glass beaker. A "button" of solder is formed from the coalescence of the solder. The "button" is cleaned and weighed. The ratio of "button" weight to original solder paste weight is the metal percent.

# Viscosity (Test #2.4.34.2)

**Objective:** The purpose of this test is to determine the viscosity of a specific lot of solder paste. Viscosity testing is a fundamental test that ensures consistent performance from lot-to-lot.

**Procedure:** Approximately 500g of solder paste is stabilized at 25 +/- 1°C and the viscosity is measured using a Malcom spiral pump viscometer at 5rpm's. The results are measured and compared to the nominal value. Solder paste lots with values outside the expected variation (USL and LSL) need to be investigated for possible performance related issues.

#### SAC305 Indium5.8LS Metal Load Chart 95 94 93 92 91 90 89 88 87 86 85 PS2595 PS3000 PS3010 PS3572 PS3573 PS3566 PS3668 PS3668 PS3668 PS3668 PS3666 PS4440 PS4440 PS4440 PS4830 PS4830 PS4830 PS4831 PS \$1344 \$1351 \$1351 \$1471 \$1824 \$1829 \$1889 S5146 S5001 Lot

		_				_		_	_			
Sample Results												
Lot Number	10 rpm (3 min)	3 rpm (6 min)	4 rpm (3 min)	5 rpm (3 min)	10 rpm (3 min)	20 rpm (1 min)	30 rpm (1 min)	10 rpm (1 min)	SSF			
PS001	1530	4140	3290	2850	1660	1035	804	1629	.7117			
PS002	1400	3680	2930	2470	1500	950	700	1430	.7207			
PS003	1490	4800	3130	2700	1415	955	708	1402	.8312			
PS004	1421	4220	3310	2750	1585	986	775	1552	.7360			
PS005	1503	3860	3140	2680	1625	1021	792	1580	.6879			

# Solder Ball (Test #2.4.43)

**Objective:** The purpose of this test is to validate soldering performance of a specific lot of solder paste. Solder ball testing is a fundamental test that ensures consistent performance for lot-to-lot.

**Procedure:** Three small deposits of solder paste are printed onto a ceramic coupon and reflowed at a temperature of approximately 240°C (for Sn/Ag/Cu alloys). The coupon is then inspected to ensure complete coalescence of the solder paste, and that there are no extraneous solder balls in the flux pool. Results are compared to images in the J-STD-005 to determine whether it passes or fails.

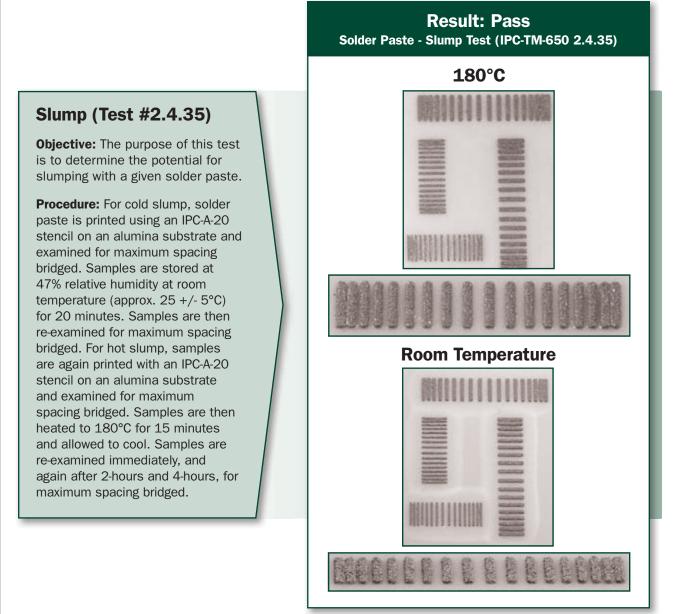
### Typical Result and Image: Pass, Preferred





#### askus@indium.com

# **5.8LS Product Level Testing**



# **Results and Image: Pass**

### Wetting (Test #2.4.45)

**Objective:** The purpose of this test is to ensure that the solder paste has sufficient capability to wet to a copper substrate.

**Procedure:** Solder paste is printed onto a clean copper coupon and reflowed using the manufacturers recommended reflow profile. The coupon is then inspected to ensure uniform wetting and no evidence of de-wetting or non-wetting.



# Example of Certificate of Analysis and Conformance for Solder Powder Products

PRODUCT	CERTIFICATION
---------	---------------

Product: 96.5Sn 3.0Ag .5Cu / -325+500

Alloy Integrit	х <b>у</b>								
Major Elei	ments:	Sn	96.390	)%	R	eported by:	LAZ		
		Ag	3.068	3 %	Test	Method(s):	AC		
		Cu	0.50	7 %					
RoHS		Actual		RoHS Max	7	Impur	ities		
Compliance:	Pb	0.0132	%	0.1000%	0.002	1% Bi			
	Cd	Not De	tected	0.0100%	0.002	6% Fe			
	Total Cr	Not De	tected	0.1000%	0.003	3% In			
	Hg	Not De	tected	0.1000%	0.013	2% Pb			
Indium certifies th	at this produc	t meets Ro	HS requireme	nts if Pb	0.0118	3% Sb			
or Cd is not a part	•								
<99.9% pure is no									
directive for any a			•						
flame retardant in				accury					
	no produot.				Total:	0.0327%	(327 PPM)	>99.9% Pure	
Powder Size	Dictributi	ioni					Oxide:	0.069 %	
Powder Size	DISTINUT	1011.					Oxide.	0.003 /8	•
+270	- 0%	, D							
-270/+325	- 1.1	%					Reported by:	KMB	
-325/+400	- 36	.1%					Test Method(s):	BD	
-400/+450	- 31	.5%							
-450/+500	- 30	.5%				Vis	ual Inspection:	Acceptabl	le
-500/+635	- 0.6	8%							
-635	- 0%	, D							
	Repor	ted by:	PR				Reported by:	KMB	
	Test Met	,	SA				Test Method(s):	MS @ 100x	
	1 COLIMEL	100(3).	07				1031 Method(3).		

Comments:

#### - CONFORMANCE STATEMENT -

Indium Corporation of America certifies that all the material used in the manufacture of this order has been made in accordance with its standard procedures and practices. Test reports to substantiate the same are retained in Indium Corporation's files and are available for your examination during the agreed upon time.

APPROVING OFFICER

a Palma Nicole A. Palma

Quality Technician

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Director, Corporate Quality



# Indium5.8LS Halogen-Free Testing

### Ion Chromatography and Titration do not Guarantee Halogen-free

Much of the electronics manufacturing industry agrees that the best method for determining the halogen content of a flux or solder paste is through the use of an oxygen bomb combustion followed by ion chromatography (IC) test. Particularly for solder paste, there is still some disagreement as to the best way to conduct this test. When running an oxygen bomb combustion, you cannot have any metal in the test chamber (i.e. solder powder). Therefore proposed methods are all based on the EN 14582 Test Method with variations only in pre-preparation of the solder paste.

# Oxygen Bomb Combustion Followed by Ion Chromatography (EN 14582)

This test method involves subjecting a sample of flux to an oxygen bomb combustion in which all of the organic material is burnt off at very high temperatures. The remaining ash consists of the halogens and other inorganic materials. That ash is the run through ion chromatography in which a true reading of halide content can be determined. Any covalently bonded halides have those bonds broken through the oxygen bomb process.

### **Testing the Raw Flux**

The flux is obtained prior to the manufacturing process in which it is mixed with the powder or the flux can be separated from the powder if already in the paste form. Approximately 1 g of the flux is placed into the oxygen bomb crucible and the test is run and followed by IC. This is the simplest of all proposed procedures but does not assess the real concern which is the amount of halogens remaining on the circuit board following reflow. However, assuming that none of the halogen volatilizes (safe assumption), then you can calculate the total halogens based on the flux residue remaining after reflow (typically 40-50%). The percentage of flux residue can be determined gravimetrically (weigh the flux, reflow it, and weigh the remaining residue) or through TGA.

# Testing the Reflowed Flux Residue

A sample of solder paste is reflowed in an aluminum pan and approximately 1 g of the residue is scraped into the oxygen bomb crucible. The advantage of this test is that you don't have to run an additional calculation since the IC results will assess exactly the amount of halogens in the flux residue. The assumption with this test is that the flux residue is homogeneous. Also the process of scraping the residue may remove other materials, particularly if this test is adapted to testing residue on the PCB.



For more information on Halogen-free issues visit: www.halogen-free.com

Test Method #1 (Raw Flux)											
Analyses Result N/D EMT Reporting Limit Units Analyzed Weight											
Anions by Ion Chromatog	raphy		Metho	d: EN 1458	2						
Bromide	<105	105	mg/Kg	2/1/08	<0.0000525 g						
Chloride <118 118 mg/Kg 1/31/08 <0.0000											
			Sample	Weight as	s Received: 0.5 g						

Total Weight of Compounds Analyzed: <0.0001 g

Test Method #2 (Reflowed Flux)					
Analyses	Result N/D	EMT Reporting Limit	Units	Date Analyzed	Weight
Anions by Ion Chromatography		Method: EN 14582			
Bromide	<82.6	82.6	mg/Kg	1/31/08	<0.0000165 g
Chloride	<186	186	mg/Kg	1/31/08	<0.0000372 g
Sample Weight as Received: 0.2 g Total Weight of Compounds Analyzed: <0.0001 g					

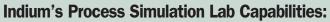
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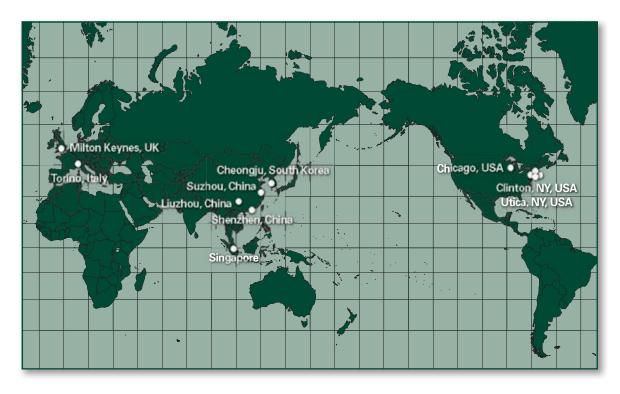
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